



# PALCE22V10 Family

## 24-Pin EE CMOS Versatile PAL Device

### DISTINCTIVE CHARACTERISTICS

- As fast as 5 ns propagation delay and 142.8 MHz  $f_{MAX}$  (external)
- Low-power EE CMOS
- 10 macrocells programmable as registered or combinatorial, and active high or active low to match application needs
- Varied product term distribution allows up to 16 product terms per output for complex functions
- Global asynchronous reset and synchronous preset for initialization
- Power-up reset for initialization and register preload for testability
- Extensive third-party software and programmer support through FusionPLD partners
- 24-pin SKINNYDIP, 24-pin SOIC, 24-pin Flat-pack and 28-pin PLCC and LCC packages save space
- 5 ns and 7.5 ns versions utilize split leadframes for improved performance

### GENERAL DESCRIPTION

The PALCE22V10 provides user-programmable logic for replacing conventional SSI/MSI gates and flip-flops at a reduced chip count.

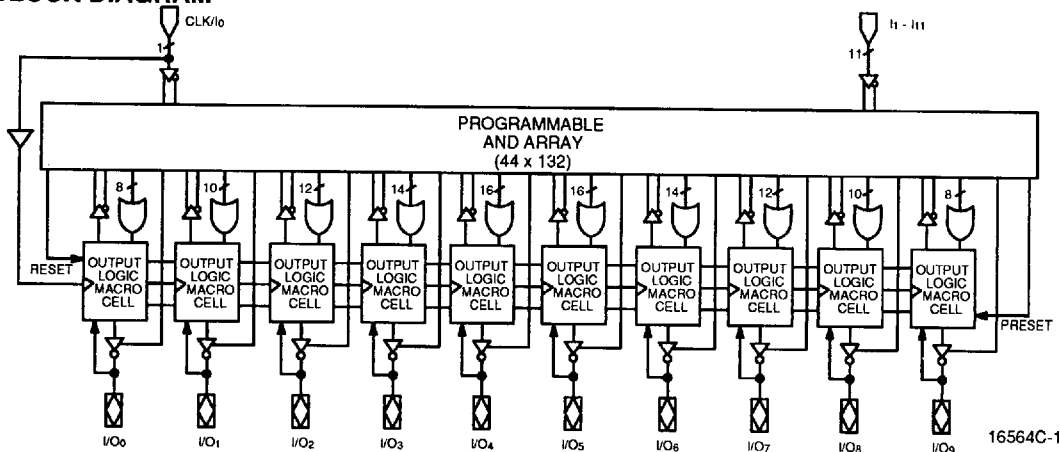
The PAL device implements the familiar Boolean logic transfer function, the sum of products. The PAL device is a programmable AND array driving a fixed OR array. The AND array is programmed to create custom product terms, while the OR array sums selected terms at the outputs.

The product terms are connected to the fixed OR array with a varied distribution from 8 to 16 across the outputs (see Block Diagram). The OR sum of the products feeds the output macrocell. Each macrocell can be programmed as registered or combinatorial, and active high or active low. The output configuration is

determined by two bits controlling two multiplexers in each macrocell.

AMD's FusionPLD program allows PALCE22V10 designs to be implemented using a wide variety of popular industry-standard design tools. By working closely with the FusionPLD partners, AMD certifies that the tools provide accurate, quality support. By ensuring that third-party tools are available, costs are lowered because a designer does not have to buy a complete set of new tools for each device. The FusionPLD program also greatly reduces design time since a designer can use a tool that is already installed and familiar. Please refer to the PLD Software Reference Guide for certified development systems and the Programmer Reference Guide for approved programmers.

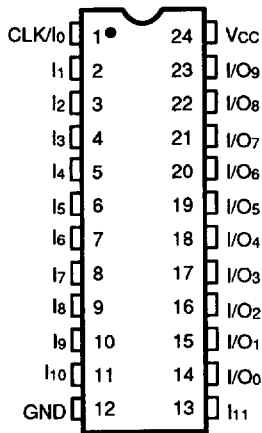
### BLOCK DIAGRAM



## CONNECTION DIAGRAMS

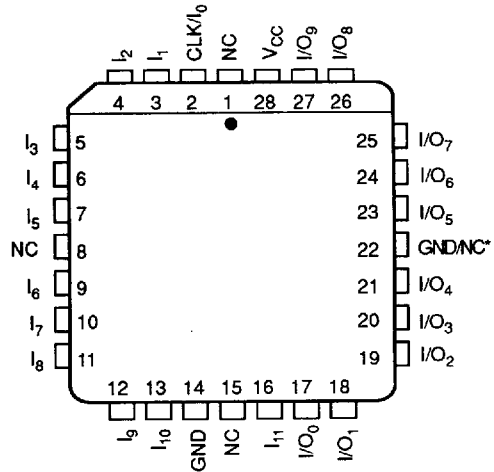
### Top View

#### SKINNYDIP/SOIC/FLATPACK



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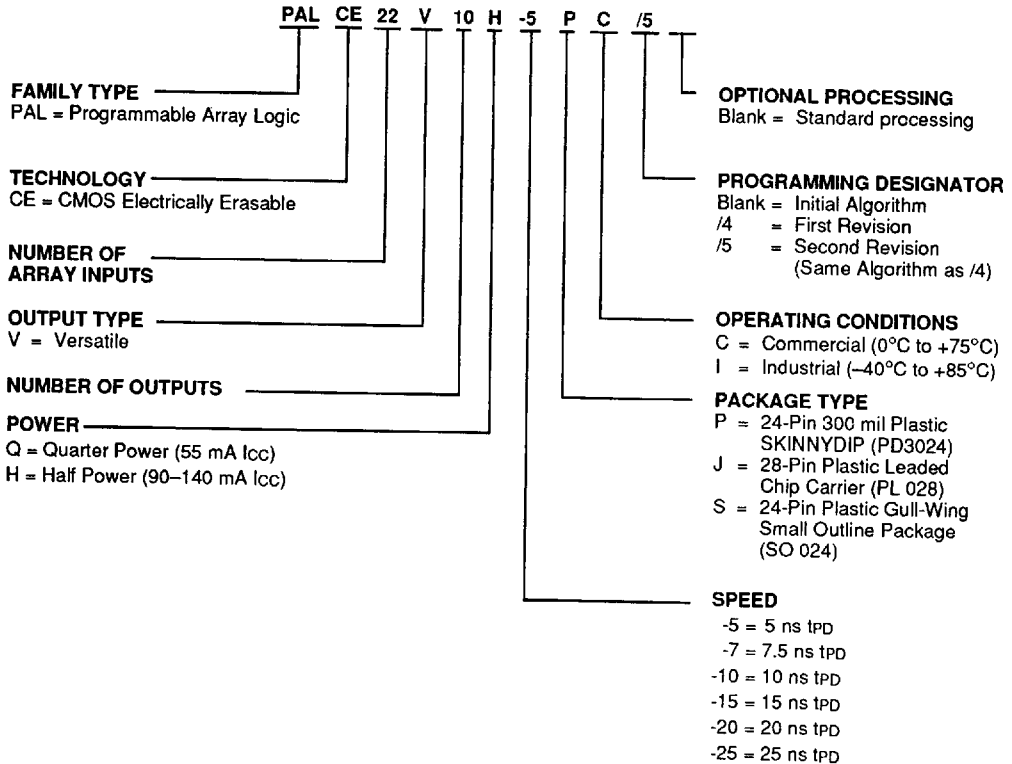
#### PLCC/LCC



## ORDERING INFORMATION

### Commercial and Industrial Products

AMD programmable logic products for commercial and industrial applications are available with several ordering options. The order number (Valid Combination) is formed by a combination of:



Valid Combinations		
PALCE22V10-5	JC	/5
PALCE22V10H-7	PC, JC, SC	
PALCE22V10H-10	PC, JC, SC, PI, JI	
PALCE22V10Q-10	PC, JC, SC	
PALCE22V10H-15	PC, JC, SC, PI, JI	Blank, /5, /4
PALCE22V10Q-15	PC, JC	/5
PALCE22V10H-20	PI, JI	/4
PALCE22V10H-25	PC, JC, SC, PI, JI	Blank, /4
PALCE22V10Q-25	PC, JC	

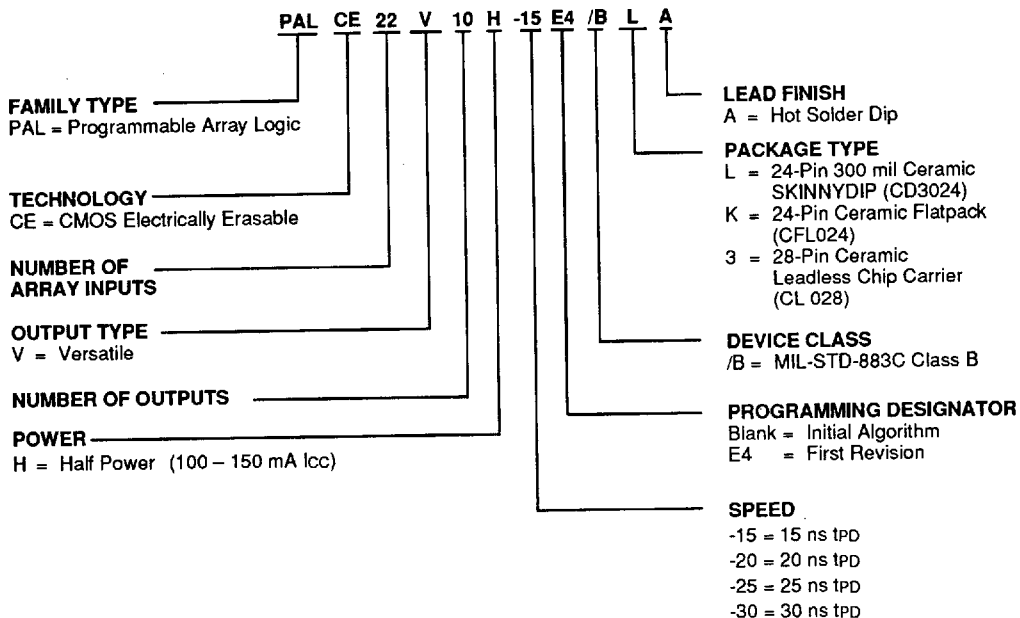
#### Valid Combinations

Valid Combinations lists configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

## ORDERING INFORMATION

### APL Products

AMD programmable logic products for Aerospace and Defense applications are available with several ordering options. APL (Approved Products List) products are fully compliant with MIL-STD-883 requirements. The order number (Valid Combination) is formed by a combination of:



Valid Combinations		
PALCE22V10H-15	E4	/BLA, /BKA, /B3A
PALCE22V10H-20	Blank, E4	
PALCE22V10H-25		
PALCE22V10H-30		

#### Valid Combinations

Valid Combinations lists configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

#### Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

#### Military Burn-In

Military burn-in is in accordance with the current revision of MIL-STD-883, Test Methods 1015, Conditions A through E. Test conditions are selected at AMD's option.

## FUNCTIONAL DESCRIPTION

The PALCE22V10 allows the systems engineer to implement the design on-chip, by programming EE cells to configure AND and OR gates within the device, according to the desired logic function. Complex interconnections between gates, which previously required time-consuming layout, are lifted from the PC board and placed on silicon, where they can be easily modified during prototyping or production.

Product terms with all connections opened assume the logical HIGH state; product terms connected to both true and complement of any single input assume the logical LOW state.

The PALCE22V10 has 12 inputs and 10 I/O macrocells. The macrocell Figure 1 allows one of four potential output configurations; registered output or combinatorial I/O, active high or active low (see Figure 1). The configuration choice is made according to the user's design

specification and corresponding programming of the configuration bits  $S_0 - S_1$ . Multiplexer controls are connected to ground (0) through a programmable bit, selecting the "0" path through the multiplexer. Erasing the bit disconnects the control line from GND and it is driven to a high level, selecting the "1" path.

The device is produced with a EE cell link at each input to the AND gate array, and connections may be selectively removed by applying appropriate voltages to the circuit. Utilizing an easily-implemented programming algorithm, these products can be rapidly programmed to any customized pattern.

### Variable Input/Output Pin Ratio

The PALCE22V10 has twelve dedicated input lines, and each macrocell output can be an I/O pin. Buffers for device inputs have complementary outputs to provide user-programmable input signal polarity. Unused input pins should be tied to  $V_{CC}$  or GND.

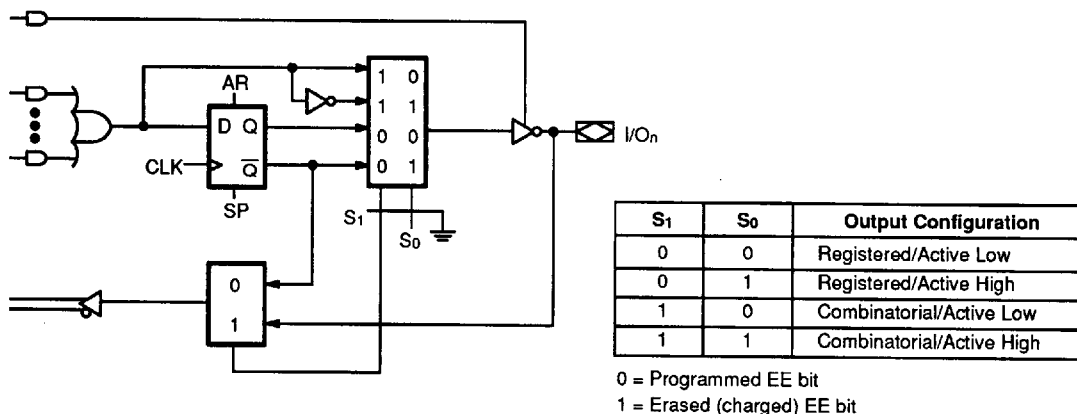


Figure 1. Output Logic Macrocell Diagram

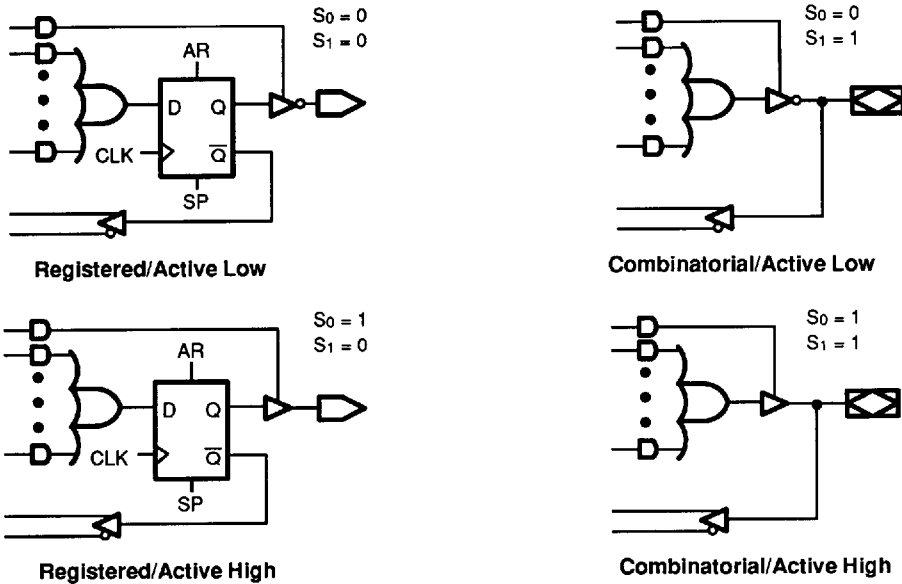
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## Registered Output Configuration

Each macrocell of the PALCE22V10 includes a D-type flip-flop for data storage and synchronization. The flip-flop is loaded on the LOW-to-HIGH transition of the clock input. In the registered configuration ( $S_1 = 0$ ), the array feedback is from  $\bar{Q}$  of the flip-flop.

## Combinatorial I/O Configuration

Any macrocell can be configured as combinatorial by selecting the multiplexer path that bypasses the flip-flop ( $S_1 = 1$ ). In the combinatorial configuration the feedback is from the pin.



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Figure 2. Macrocell Configuration Options

## Programmable Three-State Outputs

Each output has a three-state output buffer with three-state control. A product term controls the buffer, allowing enable and disable to be a function of any product of device inputs or output feedback. The combinatorial output provides a bidirectional I/O pin, and may be configured as a dedicated input if the buffer is always disabled.

## Programmable Output Polarity

The polarity of each macrocell output can be active high or active low, either to match output signal needs or to reduce product terms. Programmable polarity allows Boolean expressions to be written in their most compact form (true or inverted), and the output can still be of the desired polarity. It can also save "DeMorganizing" efforts.

Selection is controlled by programmable bit  $S_0$  in the output macrocell, and affects both registered and combinatorial outputs. Selection is automatic, based on the design specification and pin definitions. If the pin definition and output equation have the same polarity, the output is programmed to be active high ( $S_0 = 1$ ).

## Preset/Reset

For initialization, the PALCE22V10 has Preset and Reset product terms. These terms are connected to all registered outputs. When the Synchronous Preset (SP) product term is asserted high, the output registers will be loaded with a HIGH on the next LOW-to-HIGH clock transition. When the Asynchronous Reset (AR) product term is asserted high, the output registers will be immediately loaded with a LOW independent of the clock.

Note that preset and reset control the flip-flop, not the output pin. The output level is determined by the output polarity selected.

## Power-Up Reset

All flip-flops power-up to a logic LOW for predictable system initialization. Outputs of the PALCE22V10 will depend on the programmed output polarity. The  $V_{cc}$  rise must be monotonic and the reset delay time is 1000 ns maximum.

## Register Preload

The register on the PALCE22V10 can be preloaded from the output pins to facilitate functional testing of complex state machine designs. This feature allows direct loading of arbitrary states, making it unnecessary to cycle through long test vector sequences to reach a desired state. In addition, transitions from illegal states can be verified by loading illegal states and observing proper recovery.

## Security Bit

After programming and verification, a PALCE22V10 design can be secured by programming the security EE bit. Once programmed, this bit defeats readback of the internal programmed pattern by a device programmer, securing proprietary designs from competitors. When the security bit is programmed, the array will read as if every bit is erased, and preload will be disabled.

The bit can only be erased in conjunction with erasure of the entire pattern.

## Programming and Erasing

The PALCE22V10 can be programmed on standard logic programmers. It also may be erased to reset a previously configured device back to its virgin state. Erasure is automatically performed by the programming hardware. No special erase operation is required.

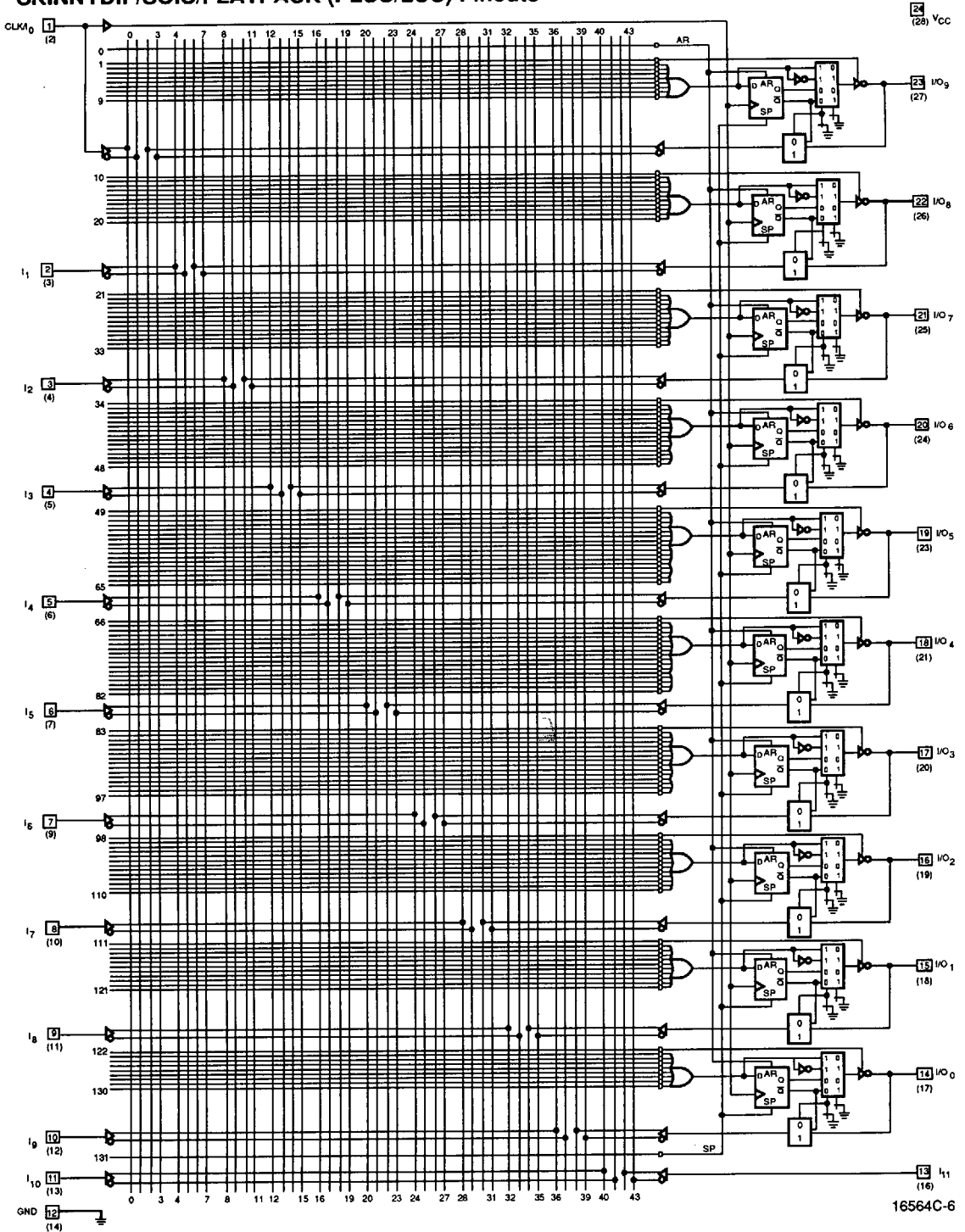
## Quality and Testability

The PALCE22V10 offers a very high level of built-in quality. The erasability of the device provides a direct means of verifying performance of all AC and DC parameters. In addition, this verifies complete programmability and functionality of the device to provide the highest programming yields and post-programming functional yields in the industry.

## Technology

The high-speed PALCE22V10 is fabricated with AMD's advanced electrically erasable (EE) CMOS process. The array connections are formed with proven EE cells. Inputs and outputs are designed to be compatible with TTL devices. This technology provides strong input clamp diodes, output slew-rate control, and a grounded substrate for clear switching.

**LOGIC DIAGRAM**  
**SKINNYDIP/SOIC/FLATPACK (PLCC/LCC) Pinouts**





## ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to +150°C
Ambient Temperature with Power Applied	-55°C to +125°C
Supply Voltage with Respect to Ground	-0.5 V to +7.0 V
DC Input Voltage	-0.5 V to $V_{CC} + 1.0$ V
DC Output or I/O Pin Voltage	-0.5 V to $V_{CC} + 1.0$ V
Static Discharge Voltage	2001 V
Latchup Current ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ )	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

## OPERATING RANGES

### Commercial (C) Devices

Ambient Temperature ( $T_A$ )	Operating in Free Air	0°C to +75°C
Supply Voltage ( $V_{CC}$ ) with Respect to Ground		+4.75 V to +5.25 V

Operating Ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over COMMERCIAL operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -3.2$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$	2.4		V
$V_{OL}$	Output LOW Voltage	$I_{OL} = 16$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.4	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 1)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = V_{CC}$ , $V_{CC} = \text{Max}$ (Note 2)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 2)		-100	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = V_{CC}$ , $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		10	$\mu\text{A}$
$I_{OZL}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		-100	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{OUT} = 0.5$ V, $V_{CC} = \text{Max}$ (Note 3)	-30	-130	mA
$I_{CC}$ (Static)	Supply Current	Outputs Open, ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$		125	mA
$I_{CC}$ (Dynamic)	Supply Current	Outputs Open, ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$ , $f = 25$ MHz		140	mA

### Notes:

1. These are absolute values with respect to the device ground and all overshoots due to system and tester noise are included.
2. I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OZL}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
3. Not more than one output should be tested at a time. Duration of the short-circuit test should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation.

**CAPACITANCE (Note 1)**

Parameter Symbol	Parameter Description	Test Conditions		Typ	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0 V	V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C f = 1 MHz	5	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0 V		8	

**Note:**

1. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

**SWITCHING CHARACTERISTICS over COMMERCIAL operating ranges (Note 2)**

Parameter Symbol	Parameter Description		-5		Unit
			Min	Max	
t <sub>PD</sub>	Input or Feedback to Combinatorial Output		1	5	ns
t <sub>S1</sub>	Setup Time from Input or Feedback		3		ns
t <sub>S2</sub>	Setup Time from SP to Clock		4		ns
t <sub>H</sub>	Hold Time		0		ns
t <sub>CO</sub>	Clock to Output		1	4	ns
t <sub>SKEWR</sub>	Skew Between Registered Outputs (Note 3)			0.5	ns
t <sub>AR</sub>	Asynchronous Reset to Registered Output			7.5	ns
t <sub>ARW</sub>	Asynchronous Reset Width		4.5		ns
t <sub>ARR</sub>	Asynchronous Reset Recovery Time		4.5		ns
t <sub>SPR</sub>	Synchronous Preset Recovery Time		4.5		ns
t <sub>WL</sub>	Clock Width	LOW	2.5		ns
t <sub>WH</sub>		HIGH	2.5		ns
f <sub>MAX</sub>	Maximum Frequency (Note 4)	External Feedback	1/(t <sub>S</sub> + t <sub>CO</sub> )	142.8	MHz
		Internal Feedback (f <sub>CNT</sub> )		150	MHz
		No Feedback	1/(t <sub>WH</sub> + t <sub>WL</sub> )	200	MHz
t <sub>EA</sub>	Input to Output Enable Using Product Term Control			6	ns
t <sub>ER</sub>	Input to Output Disable Using Product Term Control			5.5	ns

**Notes:**

2. See Switching Test Circuit for test conditions.
3. Skew is measured with all outputs switching in the same direction.
4. These parameters are not 100% tested, but are calculated at initial characterization and at any time the design is modified where frequency may be affected.

## ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to +150°C
Ambient Temperature with Power Applied	-55°C to +125°C
Supply Voltage with Respect to Ground	-0.5 V to +7.0 V
DC Input Voltage	-0.5 V to $V_{CC} + 1.0$ V
DC Output or I/O Pin Voltage	-0.5 V to $V_{CC} + 1.0$ V
Static Discharge Voltage	2001 V
Latchup Current ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ )	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

## OPERATING RANGES

### Commercial (C) Devices

Ambient Temperature ( $T_A$ )	Operating in Free Air	0°C to +75°C
Supply Voltage ( $V_{CC}$ ) with Respect to Ground		+4.75 V to +5.25 V

Operating Ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over COMMERCIAL operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -3.2$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$	2.4		V
$V_{OL}$	Output LOW Voltage	$I_{OL} = 16$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.4	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 1)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = V_{CC}$ , $V_{CC} = \text{Max}$ (Note 2)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 2)		-100	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = V_{CC}$ , $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		10	$\mu\text{A}$
$I_{OZL}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		-100	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{OUT} = 0.5$ V, $V_{CC} = \text{Max}$ $T_A = 25^\circ\text{C}$ (Note 3)	-30	-130	mA
$I_{CC}$ (Static)	Supply Current	Outputs Open, ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$		115	mA
$I_{CC}$ (Dynamic)	Supply Current	Outputs Open, ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$ , $f = 25$ MHz		140	mA

### Notes:

- These are absolute values with respect to the device ground and all overshoots due to system and tester noise are included.
- I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OZL}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
- Not more than one output should be tested at a time. Duration of the short-circuit test should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation.

## CAPACITANCE (Note 1)

Parameter Symbol	Parameter Description	Test Conditions		Typ	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0 V	V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C f = 1 MHz	5	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0 V		8	

**Note:**

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## SWITCHING CHARACTERISTICS over COMMERCIAL operating ranges (Note 2)

Parameter Symbol	Parameter Description	-7				Unit
		PDIP		PLCC		
		Min	Max	Min	Max	
t <sub>PD</sub>	Input or Feedback to Combinatorial Output	1	7.5	1	7.5	ns
t <sub>S1</sub>	Setup Time from Input or Feedback	5		4.5		ns
t <sub>S2</sub>	Setup Time from SP to Clock	6		6		ns
t <sub>H</sub>	Hold Time	0		0		ns
t <sub>CO</sub>	Clock to Output	1	5	1	4.5	ns
t <sub>SKWR</sub>	Skew Between Registered Outputs (Note 3)		1		1	ns
t <sub>AR</sub>	Asynchronous Reset to Registered Output		10		10	ns
t <sub>ARW</sub>	Asynchronous Reset Width	7		7		ns
t <sub>ARR</sub>	Asynchronous Reset Recovery Time	7		7		ns
t <sub>SPR</sub>	Synchronous Preset Recovery Time	7		7		ns
t <sub>WL</sub>	Clock Width	LOW		3.5	3.0	ns
t <sub>WH</sub>		HIGH		3.5	3.0	ns
f <sub>MAX</sub>	Maximum Frequency (Note 4)	External Feedback	1/(t <sub>S</sub> + t <sub>CO</sub> )	100	111	MHz
		Internal Feedback (f <sub>CNT</sub> )		125	133	MHz
		No Feedback	1/(t <sub>WH</sub> + t <sub>WL</sub> )	142.8	166	MHz
t <sub>EA</sub>	Input to Output Enable Using Product Term Control		7.5		7.5	ns
t <sub>ER</sub>	Input to Output Disable Using Product Term Control		7.5		7.5	ns

**Notes:**

2. See Switching Test Circuit for test conditions.
3. Skew is measured with all outputs switching in the same direction.
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Supply Voltage with Respect to Ground .....	-0.5 V to +7.0 V
DC Input Voltage .....	-0.5 V to $V_{CC} + 1.0$ V
DC Output or I/O Pin Voltage .....	-0.5 V to $V_{CC} + 1.0$ V
Static Discharge Voltage .....	2001 V
Latchup Current ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ ) .....	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

## OPERATING RANGES

### Commercial (C) Devices

Ambient Temperature ( $T_A$ ) Operating in Free Air .....	0°C to +75°C
Supply Voltage ( $V_{CC}$ ) with Respect to Ground .....	+4.75 V to +5.25 V

Operating Ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over COMMERCIAL operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
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$V_{OL}$	Output LOW Voltage	$I_{OL} = 16$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.4	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 1)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = V_{CC}$ , $V_{CC} = \text{Max}$ (Note 2)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 2)		-100	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = V_{CC}$ , $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		10	$\mu\text{A}$
$I_{OZL}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		-100	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{OUT} = 0.5$ V, $V_{CC} = \text{Max}$ $T_A = 25^\circ\text{C}$ (Note 3)	-30	-130	mA
$I_{CC}$ (Dynamic)	Supply Current	Outputs Open, ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$ , $f = 25$ MHz		120	mA

### Notes:

- These are absolute values with respect to the device ground and all overshoots due to system and tester noise are included.
- I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OZL}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
- Not more than one output should be tested at a time. Duration of the short-circuit test should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation.

## CAPACITANCE (Note 1)

Parameter Symbol	Parameter Description	Test Conditions		Typ	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0 V	V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C f = 1 MHz	5	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0 V		8	

**Note:**

1. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

## SWITCHING CHARACTERISTICS over COMMERCIAL operating ranges (Note 2)

Parameter Symbol	Parameter Description	-10		Unit
		Min	Max	
t <sub>PD</sub>	Input or Feedback to Combinatorial Output		10	ns
t <sub>S1</sub>	Setup Time from Input or Feedback	6		ns
t <sub>S2</sub>	Setup Time from SP to Clock	7		ns
t <sub>H</sub>	Hold Time	0		ns
t <sub>CO</sub>	Clock to Output		6	ns
t <sub>AR</sub>	Asynchronous Reset to Registered Output		13	ns
t <sub>ARW</sub>	Asynchronous Reset Width	8		ns
t <sub>ARR</sub>	Asynchronous Reset Recovery Time	8		ns
t <sub>SPR</sub>	Synchronous Preset Recovery Time	8		ns
t <sub>WL</sub>	Clock Width	LOW	4	ns
t <sub>WH</sub>		HIGH	4	ns
f <sub>MAX</sub>	Maximum Frequency (Note 3)	External Feedback   1/(t <sub>S</sub> + t <sub>CO</sub> )	83.3	MHz
		Internal Feedback (f <sub>CNT</sub> )	110	MHz
		No Feedback   1/(t <sub>WH</sub> + t <sub>WL</sub> )	125	MHz
t <sub>EA</sub>	Input to Output Enable Using Product Term Control		10	ns
t <sub>ER</sub>	Input to Output Disable Using Product Term Control		9	ns

**Notes:**

2. See Switching Test Circuit for test conditions.
3. These parameters are not 100% tested, but are calculated at initial characterization and at any time the design is modified where frequency may be affected.

## ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to +150°C
Ambient Temperature with Power Applied	-55°C to +125°C
Supply Voltage with Respect to Ground	-0.5 V to +7.0 V
DC Input Voltage	-0.5 V to $V_{CC} + 1.0$ V
DC Output or I/O Pin Voltage	-0.5 V to $V_{CC} + 1.0$ V
Static Discharge Voltage	2001 V
Latchup Current ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ )	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

## OPERATING RANGES

### Commercial (C) Devices

Ambient Temperature ( $T_A$ )	Operating in Free Air	0°C to +75°C
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Supply Voltage ( $V_{CC}$ ) with Respect to Ground	+4.75 V to +5.25 V
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Operating Ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over COMMERCIAL operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -3.2$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$	2.4		V
$V_{OL}$	Output LOW Voltage	$I_{OL} = 16$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.4	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 1)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = V_{CC}$ , $V_{CC} = \text{Max}$ (Note 2)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 2)		-100	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = V_{CC}$ , $V_{CC} = \text{Max}$ $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		10	$\mu\text{A}$
$I_{OZL}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		-100	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{OUT} = 0.5$ V, $V_{CC} = 5$ V $T_A = 25^\circ\text{C}$ (Note 3)	-30	-130	mA
$I_{CC}$ (Static)	Supply Current	$V_{IN} = 0$ V, Outputs Open ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$ (Note 4)		55	mA

### Notes:

- These are absolute values with respect to the device ground and all overshoots due to system and tester noise are included.
- I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OZL}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
- Not more than one output should be tested at a time. Duration of the short-circuit test should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation.
- This parameter is guaranteed worst case under test condition. Refer to the  $I_{CC}$  vs. frequency graph for typical  $I_{CC}$  characteristics.

## CAPACITANCE (Note 1)

Parameter Symbol	Parameter Description	Test Conditions		Typ	Unit
CIN	Input Capacitance	VIN = 2.0 V	VCC = 5.0 V TA = 25°C f = 1 MHz	5	pF
COU	Output Capacitance	VOU = 2.0 V		8	

**Note:**

1. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

## SWITCHING CHARACTERISTICS over COMMERCIAL operating ranges (Note 2)

Parameter Symbol	Parameter Description		-10		Unit	
			Min	Max		
tpd	Input or Feedback to Combinatorial Output			10	ns	
ts	Setup Time from Input, Feedback or SP to Clock		6		ns	
th	Hold Time		0		ns	
tco	Clock to Output			6	ns	
tAR	Asynchronous Reset to Registered Output			13	ns	
tARW	Asynchronous Reset Width		8		ns	
tARR	Asynchronous Reset Recovery Time		8		ns	
tSPR	Synchronous Preset Recovery Time		8		ns	
twl	Clock Width	LOW	4		ns	
		HIGH	4		ns	
fMAX	Maximum Frequency (Note 3)	External Feedback	1/(ts + tco)		83	MHz
		Internal Feedback (fcNT)		110	MHz	
		No Feedback	1/(tWH + twl)		125	MHz
tEA	Input to Output Enable Using Product Term Control			10	ns	
tER	Input to Output Disable Using Product Term Control			9	ns	

**Notes:**

2. See Switching Test Circuit for test conditions.
3. These parameters are not 100% tested, but are calculated at initial characterization and at any time the design is modified where frequency may be affected.



## ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to +150°C
Ambient Temperature with Power Applied	-55°C to +125°C
Supply Voltage with Respect to Ground	-0.5 V to +7.0 V
DC Input Voltage	-0.5 V to $V_{CC} + 0.5$ V
DC Output or I/O Pin Voltage	-0.5 V to $V_{CC} + 0.5$ V
Static Discharge Voltage	2001 V
Latchup Current ( $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ )	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

## OPERATING RANGES

### Commercial (C) Devices

Ambient Temperature ( $T_A$ )	Operating in Free Air	0°C to +75°C
Supply Voltage ( $V_{CC}$ ) with Respect to Ground (H/Q-15)		+4.75 V to +5.25 V
Supply Voltage ( $V_{CC}$ ) with Respect to Ground (H/Q-25)		+4.5 V to +5.5 V

Operating Ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over COMMERCIAL operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -3.2$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$	2.4		V
$V_{OL}$	Output LOW Voltage	$I_{OL} = 16$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.4	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 1)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = V_{CC}$ , $V_{CC} = \text{Max}$ (Note 2)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 2)		-100	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = V_{CC}$ , $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		10	$\mu\text{A}$
$I_{OZL}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		-100	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{OUT} = 0.5$ V, $V_{CC} = 5$ V $T_A = 25^\circ\text{C}$ (Note 3)	-30	-130	mA
$I_{CC}$	Supply Current	$V_{IN} = 0$ V, Outputs Open ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$	H	90	mA
			Q	55	

### Notes:

- These are absolute values with respect to the device ground and all overshoots due to system and tester noise are included.
- I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OZL}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
- Not more than one output should be tested at a time. Duration of the short-circuit test should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation.

## CAPACITANCE (Note 1)

Parameter Symbol	Parameter Description	Test Conditions		Typ	Unit
CIN	Input Capacitance	V <sub>IN</sub> = 2.0 V	V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C f = 1 MHz	5	pF
COUT	Output Capacitance	V <sub>OUT</sub> = 2.0 V		8	

**Note:**

1. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

## SWITCHING CHARACTERISTICS over COMMERCIAL operating ranges (Note 2)

Parameter Symbol	Parameter Description		-15		-25		Unit
			Min	Max	Min	Max	
t <sub>PD</sub>	Input or Feedback to Combinatorial Output			15		25	ns
t <sub>s</sub>	Setup Time from Input, Feedback or SP to Clock		10		15		ns
t <sub>H</sub>	Hold Time		0		0		ns
t <sub>CO</sub>	Clock to Output			10		15	ns
t <sub>AR</sub>	Asynchronous Reset to Registered Output			20		25	ns
t <sub>ARW</sub>	Asynchronous Reset Width		15		25		ns
t <sub>ARR</sub>	Asynchronous Reset Recovery Time		10		25		ns
t <sub>SPR</sub>	Synchronous Preset Recovery Time		10		25		ns
t <sub>WL</sub>	Clock Width	LOW	8		13		ns
t <sub>WH</sub>		HIGH	8		13		ns
f <sub>MAX</sub>	Maximum Frequency (Note 3)	External Feedback	1/(t <sub>s</sub> + t <sub>CO</sub> )		50	33.3	MHz
		Internal Feedback (f <sub>CNT</sub> )	58.8	35.7	MHz		
t <sub>EA</sub>	Input to Output Enable Using Product Term Control			15		25	ns
t <sub>ER</sub>	Input to Output Disable Using Product Term Control			15		25	ns

**Notes:**

2. See Switching Test Circuit for test conditions.
3. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where frequency may be affected.

## ABSOLUTE MAXIMUM RATINGS

Storage Temperature .....	-65°C to +150°C
Ambient Temperature with Power Applied .....	-55°C to +125°C
Supply Voltage with Respect to Ground .....	-0.5 V to +7.0 V
DC Input Voltage .....	-0.5 V to $V_{CC} + 0.5$ V
DC Output or I/O Pin Voltage .....	-0.5 V to $V_{CC} + 0.5$ V
Static Discharge Voltage .....	2001 V
Latchup Current ( $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$ ) ....	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

## OPERATING RANGES

### Industrial (I) Devices

Ambient Temperature ( $T_A$ ) Operating in Free Air .....	-40°C to +85°C
Supply Voltage ( $V_{CC}$ ) with Respect to Ground .....	+4.5 V to +5.5 V

Operating Ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over INDUSTRIAL operating ranges unless otherwise specified

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -3.2$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$	2.4		V
$V_{OL}$	Output LOW Voltage	$I_{OL} = 16$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.4	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 1)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 1)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = V_{CC}$ , $V_{CC} = \text{Max}$ (Note 2)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 2)		-100	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = V_{CC}$ , $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		10	$\mu\text{A}$
$I_{OLZ}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 2)		-100	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{OUT} = 0.5$ V, $V_{CC} = 5$ V $T_A = 25^\circ\text{C}$ (Note 3)	-30	-130	mA
$I_{CC}$ (Static)	Supply Current	H-20/25	$V_{IN} = 0$ V, Outputs Open ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$	100	mA
		H-10/15		110	
$I_{CC}$ (Dynamic)	Supply Current	$V_{IN} = 0$ V, Outputs Open ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$ , $f = 15$ MHz		130	mA

### Notes:

- These are absolute values with respect to the device ground and all overshoots due to system and tester noise are included.
- I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OLZ}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
- Not more than one output should be tested at a time. Duration of the short-circuit test should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation.

## CAPACITANCE (Note 1)

Parameter Symbol	Parameter Description	Test Conditions		Typ	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0 V	V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C f = 1 MHz	5	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0 V		8	

**Note:**

1. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

## SWITCHING CHARACTERISTICS over INDUSTRIAL operating ranges (Note 2)

Parameter Symbol	Parameter Description	-10		-15		-20		-25		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD</sub>	Input or Feedback to Combinatorial Output		10		15		20		25	ns
t <sub>S</sub>	Setup Time from Input, Feedback or SP to Clock	7		10		12		15		ns
t <sub>H</sub>	Hold Time	0		0		0		0		ns
t <sub>CO</sub>	Clock to Output		6		10		12		15	ns
t <sub>AR</sub>	Asynchronous Reset to Registered Output		13		20		25		25	ns
t <sub>ARW</sub>	Asynchronous Reset Width	8		15		20		25		ns
t <sub>ARR</sub>	Asynchronous Reset Recovery Time	8		10		20		25		ns
t <sub>SPR</sub>	Synchronous Preset Recovery Time	8		10		14		25		ns
t <sub>WL</sub>	Clock Width	LOW	4	8	10	13				ns
t <sub>WH</sub>		HIGH	4	8	10	13				ns
f <sub>MAX</sub>	Maximum Frequency (Note 3)	External Feedback $1/(t_s + t_{CO})$	83.3	50	41.6	33.3				MHz
		Internal Feedback (fc <sub>NT</sub> )	110	58.8	45.4	35.7				MHz
		No Feedback $1/(t_{WH} + t_{WL})$	125	83.3	50	38.5				MHz
t <sub>EA</sub>	Input to Output Enable Using Product Term Control		10	15	20	25				ns
t <sub>ER</sub>	Input to Output Disable Using Product Term Control		9	15	20	25				ns

**Notes:**

2. See Switching Test Circuit for test conditions.
3. These parameters are not 100% tested, but are calculated at initial characterization and at any time the design is modified where frequency may be affected.

## ABSOLUTE MAXIMUM RATINGS

Storage Temperature .....	-65°C to +150°C
Ambient Temperature with Power Applied .....	-55°C to +125°C
Supply Voltage with Respect to Ground .....	-0.5 V to +7.0 V
DC Input Voltage .....	-0.5 V to $V_{CC} + 1.0$ V
DC Output or I/O Pin Voltage .....	-0.5 V to $V_{CC} + 0.5$ V
Static Discharge Voltage .....	2001 V
Latchup Current ( $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ ) ...	100 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability. Programming conditions may differ. Absolute Maximum Ratings are for system design reference; parameters given are not tested.

## OPERATING RANGES

### Military (M) Devices (Note 1)

Operating Case Temperature ( $T_C$ ) .....	-55°C to +125°C
Supply Voltage ( $V_{CC}$ ) with Respect to Ground .....	+4.5 V to +5.5 V

#### Note:

1. Military products are tested at  $T_C = +25^\circ\text{C}$ ,  $+125^\circ\text{C}$  and  $-55^\circ\text{C}$ , per MIL-STD-883.

Operating Ranges define those limits between which the functionality of the device is guaranteed.

## DC CHARACTERISTICS over MILITARY operating ranges unless otherwise specified (Note 2)

Parameter Symbol	Parameter Description	Test Conditions	Min	Max	Unit
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -2.0$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$	2.4		V
$V_{OL}$	Output LOW Voltage	$I_{OL} = 12$ mA $V_{IN} = V_{IH}$ or $V_{IL}$ $V_{CC} = \text{Min}$		0.4	V
$V_{IH}$	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 3)	2.0		V
$V_{IL}$	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 3)		0.8	V
$I_{IH}$	Input HIGH Leakage Current	$V_{IN} = 5.5$ V, $V_{CC} = \text{Max}$ (Note 4)		10	$\mu\text{A}$
$I_{IL}$	Input LOW Leakage Current	$V_{IN} = 0$ V, $V_{CC} = \text{Max}$ (Note 4)		-100	$\mu\text{A}$
$I_{OZH}$	Off-State Output Leakage Current HIGH	$V_{OUT} = 5.5$ V, $V_{CC} = \text{Max}$ , $V_{IN} = V_{IL}$ or $V_{IH}$ (Note 4)		10	$\mu\text{A}$
$I_{OLZ}$	Off-State Output Leakage Current LOW	$V_{OUT} = 0$ V, $V_{CC} = \text{Max}$ , $V_{IN} = V_{IH}$ or $V_{IL}$ (Note 4)		-100	$\mu\text{A}$
$I_{SC}$	Output Short-Circuit Current	$V_{OUT} = 0.5$ V, $V_{CC} = 5$ V $T_A = 25^\circ\text{C}$ (Note 5)	-50	-135	mA
$I_{CC}$	Supply Current	$V_{IN} = 0$ V, Outputs Open ( $I_{OUT} = 0$ mA), $V_{CC} = \text{Max}$	-15/-20 -25/-30	120 100	mA

#### Notes:

2. For APL products, Group A, Subgroups 1, 2 and 3 are tested per MIL-STD-883, Method 5005, unless otherwise noted.
3.  $V_{IL}$  and  $V_{IH}$  are input conditions of output tests and are not themselves directly tested.  $V_{IL}$  and  $V_{IH}$  are absolute voltages with respect to device ground and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.
4. I/O pin leakage is the worst case of  $I_{IL}$  and  $I_{OLZ}$  (or  $I_{IH}$  and  $I_{OZH}$ ).
5. Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.  $V_{OUT} = 0.5$  V has been chosen to avoid test problems caused by tester ground degradation. This parameter is not 100% tested, but is evaluated at initial characterization and at any time the design is modified where  $I_{SC}$  may be affected.

## CAPACITANCE (Note 1)

Parameter Symbol	Parameter Description	Test Conditions		Typ	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 2.0 V	V <sub>CC</sub> = 5.0 V T <sub>A</sub> = 25°C f = 1 MHz	8	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 2.0 V		9	

**Note:**

1. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

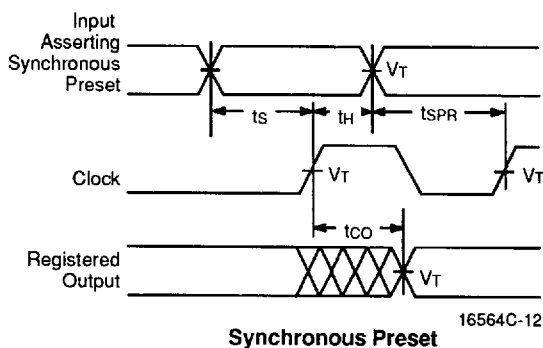
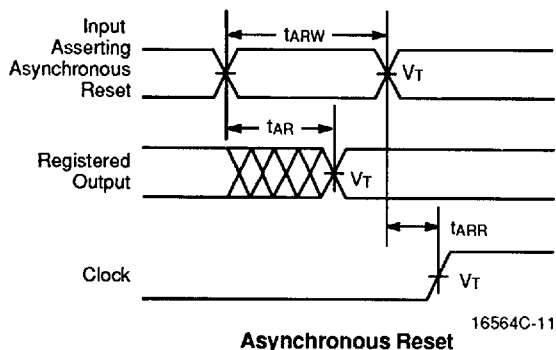
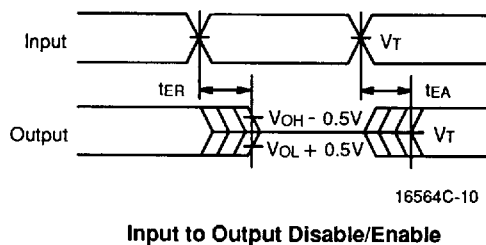
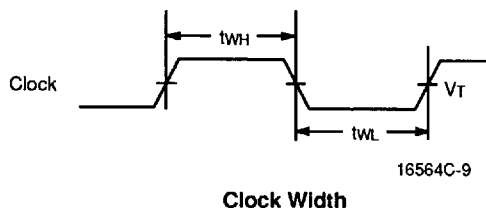
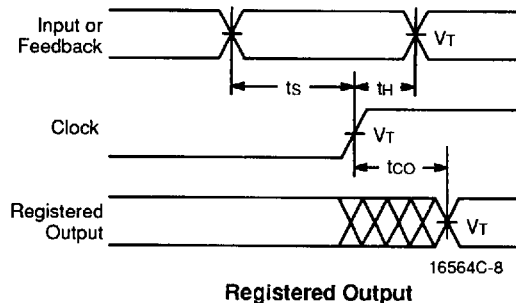
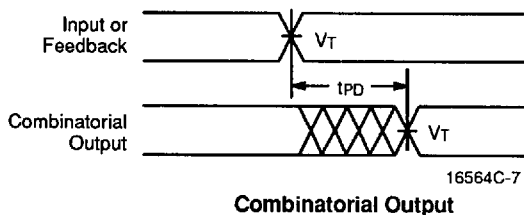
## SWITCHING CHARACTERISTICS over MILITARY operating ranges (Note 2)

Parameter Symbol	Parameter Description	-15		-20		-25		-30		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD</sub>	Input or Feedback to Combinatorial Output		15		20		25		30	ns
t <sub>S</sub>	Setup Time from Input, Feedback or SP to Clock	12		15		18		20		ns
t <sub>H</sub>	Hold Time (Note 3)	0		0		0		0		ns
t <sub>CO</sub>	Clock to Output		12		15		20		20	ns
t <sub>AR</sub>	Asynchronous Reset to Registered Output		20		25		25		30	ns
t <sub>ARW</sub>	Asynchronous Reset Width (Note 3)	15		20		25		30		ns
t <sub>ARR</sub>	Asynchronous Reset Recovery Time (Note 3)	15		20		25		30		ns
t <sub>SPR</sub>	Synchronous Preset Recovery Time	15		20		25		30		ns
t <sub>WL</sub>	Clock Width	LOW		8		15		15		ns
t <sub>WH</sub>		HIGH		8		15		15		ns
f <sub>MAX</sub>	Maximum Frequency (Note 3)	External Feedback 1/(t <sub>S</sub> + t <sub>CO</sub> )		41.6		33.3		26.3		MHz
		Internal Feedback (f <sub>CNT</sub> )		53		40		32.2		25
t <sub>EA</sub>	Input to Output Enable Using Product Term Control (Note 3)		15		20		25		25	ns
t <sub>ER</sub>	Input to Output Disable Using Product Term Control (Note 3)		15		20		25		25	ns

**Notes:**

2. See Switching Test Circuit for test conditions. For APL products Group A, Subgroups 7, 8, 9, 10, and 11 are tested per MIL-STD-883, Method 5005, unless otherwise noted.
3. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where these parameters may be affected.

## SWITCHING WAVEFORMS



**Notes:**

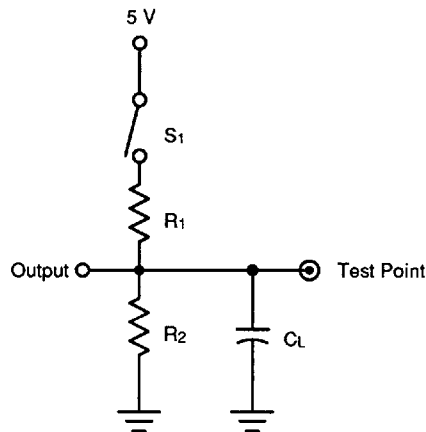
1.  $V_T = 1.5 V$ .
2. Input pulse amplitude 0 V to 3.0 V.
3. Input rise and fall times 2 ns – 5 ns typical.

## KEY TO SWITCHING WAVEFORMS

WAVEFORM	INPUTS	OUTPUTS
	Must be Steady	Will be Steady
	May Change from H to L	Will be Changing from H to L
	May Change from L to H	Will be Changing from L to H
	Don't Care, Any Change Permitted	Changing, State Unknown
	Does Not Apply	Center Line is High-Impedance "Off" State

KS000010-PAL

## SWITCHING TEST CIRCUIT



16564C-13

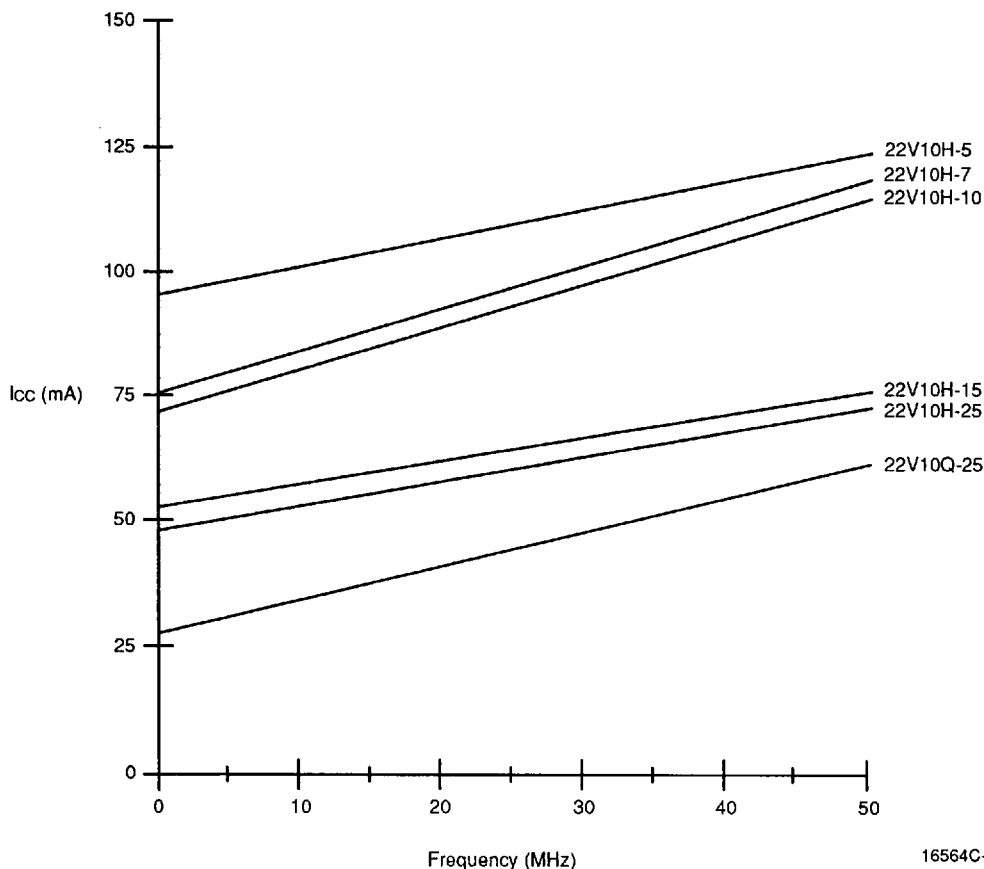
Specification	S <sub>1</sub>	C <sub>L</sub>	Commercial		Military		Measured Output Value
			R <sub>1</sub>	R <sub>2</sub>	R <sub>1</sub>	R <sub>2</sub>	
t <sub>PD</sub> , t <sub>CO</sub>	Closed	50 pF	300 Ω	All except H-5/7: 390 Ω	390 Ω	750 Ω	1.5 V
t <sub>EA</sub>	Z → H: Open Z → L: Closed			H-5/7: 300 Ω			1.5 V
t <sub>ER</sub>	H → Z: Open L → Z: Closed	5 pF					H → Z: V <sub>OH</sub> - 0.5 V L → Z: V <sub>OL</sub> + 0.5 V

0257526 0035072 067



## TYPICAL $I_{CC}$ CHARACTERISTICS

$V_{CC} = 5.0 \text{ V}$ ,  $T_A = 25^\circ\text{C}$



16564C-14

### $I_{CC}$ vs. Frequency

The selected "typical" pattern utilized 50% of the device resources. Half of the macrocells were programmed as registered, and the other half were programmed as combinatorial. Half of the available product terms were used for each macrocell. On any vector, half of the outputs were switching.

By utilizing 50% of the device, a midpoint is defined for  $I_{CC}$ . From this midpoint, a designer may scale the  $I_{CC}$  graphs up or down to estimate the  $I_{CC}$  requirements for a particular design.

## ENDURANCE CHARACTERISTICS

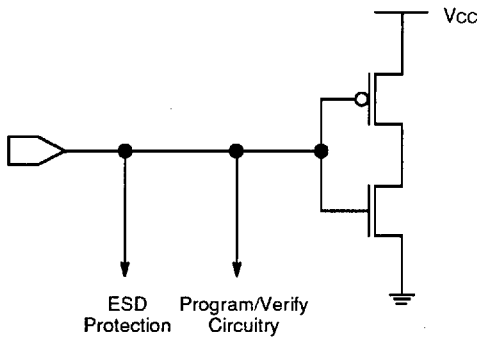
The PALCE22V10 is manufactured using AMD's advanced Electrically Erasable process. This technology uses an EE cell to replace the fuse link used in bipolar

parts. As a result, the device can be erased and reprogrammed—a feature which allows 100% testing at the factory.

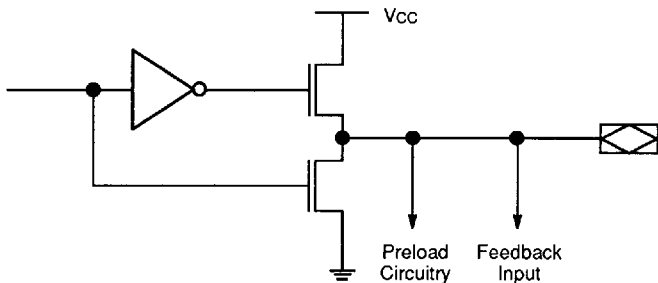
### Endurance Characteristics

Symbol	Parameter	Test Conditions	Min	Unit
tDR	Min Pattern Data Retention Time	Max Storage Temperature	10	Years
		Max Operating Temperature (Military)	20	Years
N	Min Reprogramming Cycles	Normal Programming Conditions	100	Cycles

### INPUT/OUTPUT EQUIVALENT SCHEMATICS



Typical Input



Typical Output

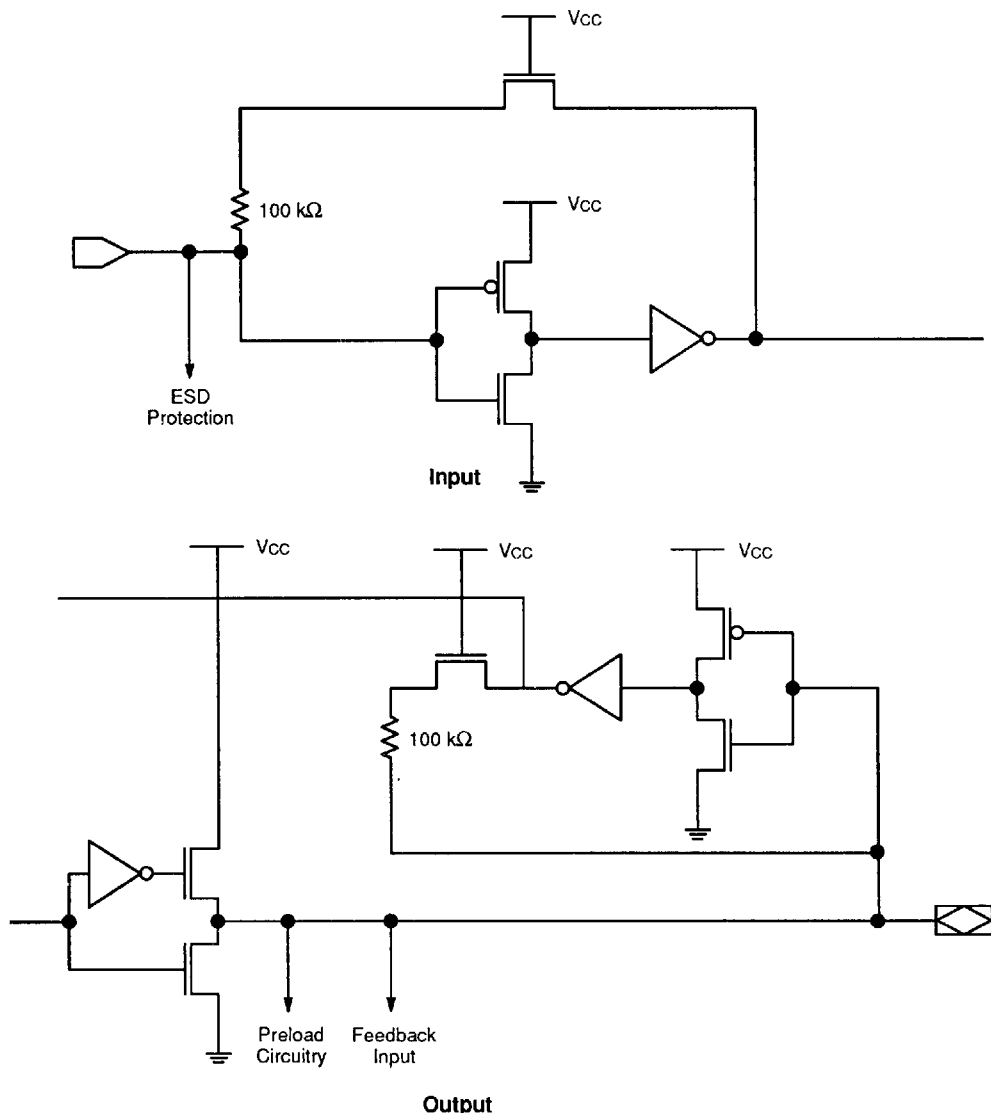
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### Bus-Friendly Inputs

The PALCE22V10H-15/25, Q-25 (Com'I) and H-20 (Ind) inputs and I/O loop back to the input after the second stage of the input buffer. This configuration reinforces

the state of the input and pulls the voltage away from the input threshold voltage. Unlike a pull-up, this configuration cannot cause contention on a bus. For an illustration of this configuration, see below.

### INPUT/OUTPUT EQUIVALENT SCHEMATICS FOR SELECTED /4 DEVICES\*



Device	Rev. Letter
PALCE22V10H-15	H
PALCE22V10H-20	
PALCE22V10H-25	
PALCE22V10Q-25	I

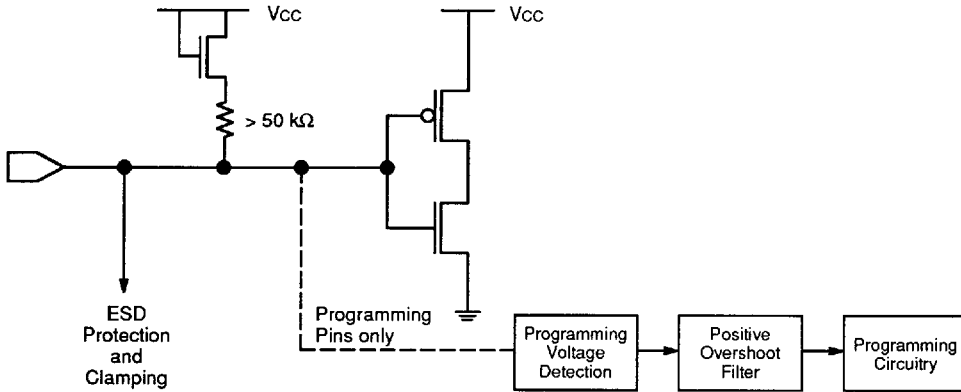
Output

## ROBUSTNESS FEATURES

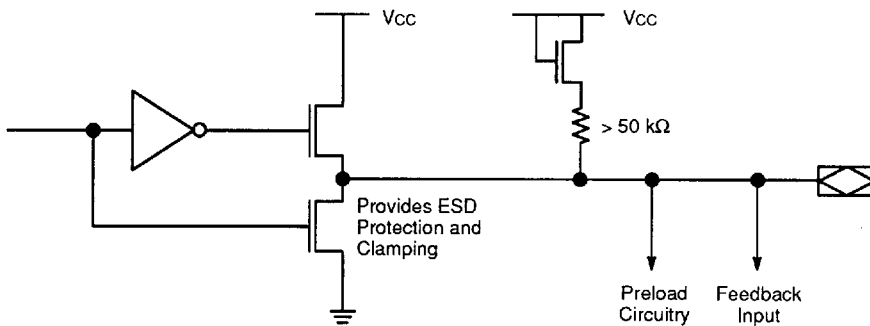
The PALCE22V10X-X/5 devices have some unique features that make them extremely robust, especially when operating in high-speed design environments. Pull-up resistors on inputs and I/O pins cause unconnected pins to default to a known state. Input clamping circuitry limits negative overshoot, eliminating the

possibility of false clocking caused by subsequent ringing. A special noise filter makes the programming circuitry completely insensitive to any positive overshoot that has a pulse width of less than about 100 ns for the /5 version. Selected /4 devices are also being retrofitted with these robustness features. See the chart below for device listing.

## INPUT/OUTPUT EQUIVALENT SCHEMATICS FOR /5 VERSION AND SELECTED /4 DEVICES\*



Typical Input



Typical Output

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Device	Rev Letter
PALCE22V10H-15	D
PALCE22V10H-25	D
PALCE22V10Q-25	F

### Topside Marking:

AMD CMOS PLD's are marked on top of the package in the following manner:

PALCEXXXX

Datecode (3 numbers) Lot ID (4 characters) — (Rev Letter)

The Lot ID and Rev Letter are separated by two spaces.

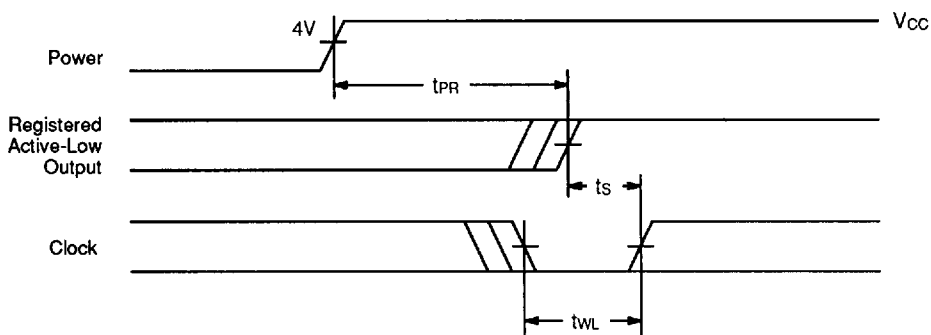
## POWER-UP RESET

The power-up reset feature ensures that all flip-flops will be reset to LOW after the device has been powered up. The output state will depend on the programmed pattern. This feature is valuable in simplifying state machine initialization. A timing diagram and parameter table are shown below. Due to the synchronous operation of the power-up reset and the wide range of ways

$V_{CC}$  can rise to its steady state, two conditions are required to ensure a valid power-up reset. These conditions are:

- The  $V_{CC}$  rise must be monotonic.
- Following reset, the clock input must not be driven from LOW to HIGH until all applicable input and feedback setup times are met.

Parameter Symbol	Parameter Description	Max	Unit
t <sub>PR</sub>	Power-up Reset Time	1000	ns
t <sub>s</sub>	Input or Feedback Setup Time	See Switching Characteristics	
t <sub>wL</sub>	Clock Width LOW		



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Power-Up Reset Waveform



## TYPICAL THERMAL CHARACTERISTICS

### PALCE22V10/4 (PALCE22V10H-15)

Measured at 25°C ambient. These parameters are not tested.

Parameter Symbol	Parameter Description	Typ		Unit	
		SKINNYDIP	PLCC		
$\theta_{jc}$	Thermal impedance, junction to case	15	16	°C/W	
$\theta_{ja}$	Thermal impedance, junction to ambient	72	54	°C/W	
$\theta_{jma}$	Thermal impedance, junction to ambient with air flow	200 lfpm air	67	49	°C/W
		400 lfpm air	60	43	°C/W
		600 lfpm air	53	37	°C/W
		800 lfpm air	46	31	°C/W

### PALCE22V10/5 (PALCE22V10H-10)

Measured at 25°C ambient. These parameters are not tested.

Parameter Symbol	Parameter Description	Typ		Unit	
		SKINNYDIP	PLCC		
$\theta_{jc}$	Thermal impedance, junction to case	20	18	°C/W	
$\theta_{ja}$	Thermal impedance, junction to ambient	73	55	°C/W	
$\theta_{jma}$	Thermal impedance, junction to ambient with air flow	200 lfpm air	66	48	°C/W
		400 lfpm air	61	43	°C/W
		600 lfpm air	55	40	°C/W
		800 lfpm air	52	37	°C/W

#### Plastic $\theta_{jc}$ Considerations

The data listed for plastic  $\theta_{jc}$  are for reference only and are not recommended for use in calculating junction temperatures. The heat-flow paths in plastic-encapsulated devices are complex, making the  $\theta_{jc}$  measurement relative to a specific location on the package surface. Tests indicate this measurement reference point is directly below the die-attach area on the bottom center of the package. Furthermore,  $\theta_{jc}$  tests on packages are performed in a constant-temperature bath, keeping the package surface at a constant temperature. Therefore, the measurements can only be used in a similar environment.

## DATA SHEET REVISION SUMMARY FOR PALCE22V10 Family

### Title

Included H-10/15/20/25 (Ind)

### Connections Diagram

For PLCC, Changed Pin 22 to include GND/NC\* and included note that pin should be grounded to guarantee performance.

### Ordering Information

Updated Valid Combinations table to include:

PALCE22V10H-10	PI,JI	/5
PALCE22V10H-15	PI,JI	/5
PALCE22V10H-20	PI,JI	/4
PALCE22V10H-25	PI,JI	/4

## DC and Switching Characteristics

### For PALCE22V10H-10/15/20/25

- added Industrial Operating Ranges

### For PALCE22V10H-15/20/25/30 (Mil)

- changed  $I_{IL}$  and  $I_{OL}$  Max from  $-10 \mu A$  to  $-100 \mu A$

### For PALCE22V10H-15 (Mil)

- changed  $t_{CO}$  Max from 8 ns to 12 ns
- changed  $f_{MAX}$  (external) from 50 to 41.6

### For PALCE22V10H-20 (Mil)

- changed  $t_{WL}$  and  $t_{WH}$  from 10 ns to 15 ns

### Included Bus-Friendly Inputs section

### Topside Marking

#### For PALCE22V10Q-25

- changed rev. letter from B to F